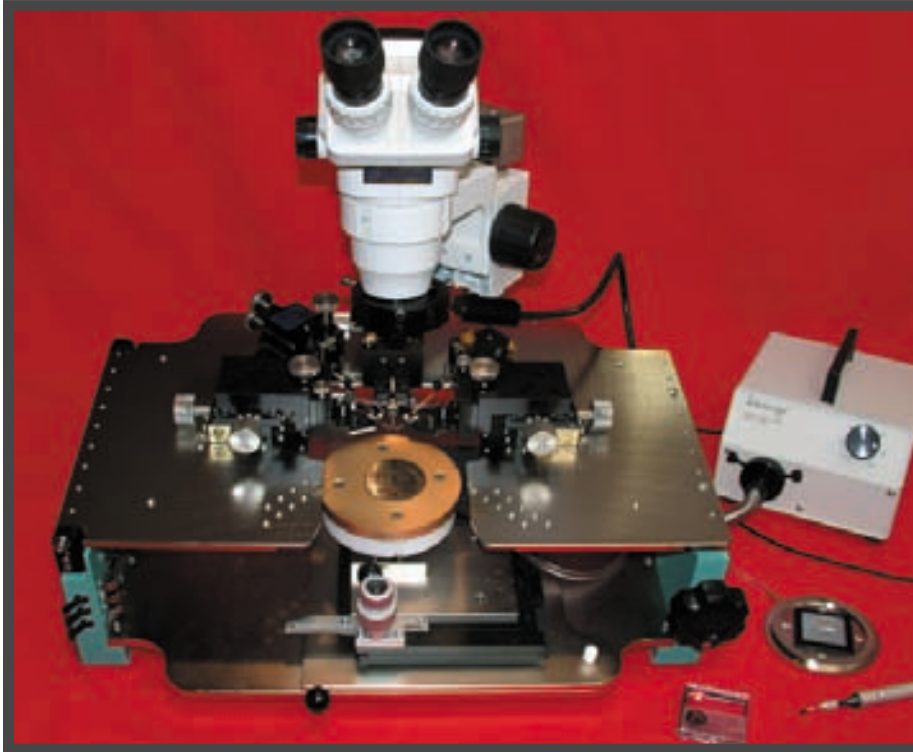




PRODUCT SELECTION GUIDE



APPLICATION DRIVEN MICROPROBING WORKSTATIONS

Jr-2700

- Microprobing Test Fixture with slide in/out 4.5" dia. stage

Jr-2727

- Personal Probe Station with X,Y, ϕ 4.5" dia. stage(2.5"X4" travel)

Jr-2745

- Personal Probe Station with X,Y, ϕ 8.5" dia. stage(6"X7" travel)

NAT-27B

- Binocular Stereo Zoom Microscope, 6.7X to 112X
- Swing arm mount for microscope

NAT-27T

- Trinocular Stereo Zoom Microscope, 6.7X to 112.5X with video adapter
- Swing arm mount for microscope

KRN-01A Low Cost

- Positioner, Magnetic - .5" X.5" travel
- Pd Alloy/Tungsten needles (5ea. type)

KRN-08A General Purpose

- Positioner, Magnetic - 5."X.5" travel
- Pd Alloy/Tungsten needles (5ea. type)

KRN-18A Microwave

- Positioner, Precise

LMS-18

- Probe Card Holder Adapter

NAT-50

- Video System

Selection Guide Overview

The Jr-27xx fixture/probe stations are high value personal and flexible microprobing environments for engineers and scientists. They are useful in electrical test for evaluation and prototype quantities of semiconductor devices and microwave assemblies. Test engineering of production probe card for new products can also be accomplished by using the probe card adapter. The following matrix can be used to help select the appropriate configuration for specific applications.

	Test Fixture	Basic Probe Station	Design Development	Test Engineering	'Chip'Design Verification
Jr-2700	X	-	-	-	-
Jr-2727	-	X	X	-	-
Jr-2745	-	-	X	X	X
NAT-27B	X	X	-	-	-
NAT-27T	-	-	X	X	X
KRN-01A	opt	1-3	-	-	-
KRN-08A	1-3	2-3(opt)	2-4	2-4	2-4
KRN-18A	2-3	2-3	-	-	-
KRN-18AKP	opt	opt	2-4	2-4	2-4
LMS-18	NR	opt	opt	X	X
NAT-50	opt	opt	X	X	X